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**(71) Applicant(s):**

NEC CORPORATION [JP/JP]; 7-1, Shiba 5-chome, Minato-ku, Tokyo 1088001 (JP) *(for all designated states)*

**(72) Inventor(s):**

LIU Jianquan; c/o NEC Corporation, 7-1, Shiba 5-chome, Minato-ku, Tokyo 1088001 (JP)

NISHIMURA Shoji; c/o NEC Corporation, 7-1, Shiba 5-chome, Minato-ku, Tokyo 1088001 (JP)

HIRAKAWA Yasufumi; c/o NEC Corporation, 7-1, Shiba 5-chome, Minato-ku, Tokyo 1088001 (JP)

**(74) Agent(s):**

HAYAMI Shinji; KDX Gotanda Bldg. 9F, 9-2, Nishi-Gotanda 7-chome, Shinagawa-ku, Tokyo 1410031 (JP)

**(54) Title (EN):** ANALYSIS SYSTEM, ANALYSIS METHOD, AND PROGRAM

**(54) Title (FR):** SYSTÈME D'ANALYSE, PROCÉDÉ D'ANALYSE ET PROGRAMME

**(54) Title (JA):** 解析システム、解析方法及びプログラム

**(57) Abstract:**

**(EN):** According to the present invention, provided is an analysis system (10) having: a generation unit (11) for generating frequency data which indicates a temporal change in occurrence frequency of a predetermined event for each processing subject; and an extraction unit (12) for extracting the processing subject in which a first characteristic appears in the frequency data as an abnormality subject candidate.

**(FR):** Selon la présente invention, l'invention concerne un système d'analyse (10) comprenant : une unité de génération (11) pour générer des données de fréquence qui indiquent un changement temporel dans la fréquence d'occurrence d'un événement prédéterminé pour chaque sujet de traitement; et une unité d'extraction (12) pour extraire le sujet de traitement dans lequel une première caractéristique apparaît dans les données de fréquence en tant que candidat sujet d'anomalie.

**(JA):** 本発明によれば、処理対象毎に、所定イベントの発生頻度の時間変化を示す頻度データを生成する生成部(11)と、頻度データにおいて第1の特徴が現れている処理対象を、異常対象候補として抽出する抽出部(12)と、を有する解析システム(10)が提供される。

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